IEEE European Test Workshop

Crown Plaza Hotel, Maastricht, The Netherlands
May 25 – 28, 2003

Call for Papers – Extended Deadline

The IEEE European Test Workshop is a well-recognized forum for presenting and discussing hot topics, trends, emerging results, and practical applications in the area of electronic-based circuit and system testing. The eighth edition of the workshop will take place in 2003 in Maastricht, The Netherlands, a town with historic roots that date back till the Roman empire, but where also the treaty on the introduction of the Euro currency was signed by the European leaders.

ETW’03 is sponsored by the IEEE Computer Society - Test Technology Technical Council (TTTC) and organized by Philips Research Laboratories.

We cordially invite you to participate and submit your contribution to ETW’03, which includes (but is not limited to) the following topics:

- Analog, Mixed-Signal, and RF Test
- ATE Hardware and Software
- ATPG and High-Level TPG
- Debug and Diagnosis
- Defect/Fault Tolerance and Reliability
- Design Verification/Validation
- Emerging Testability Standards
- Failure Analysis, Defect and Fault Modeling
- Fault Simulation
- FPGA Test
- High-Level DFT
- IDDQ Test
- Low-Cost Testers
- Memory and Processor Test
- MEMS Testing
- On-Line and Off-Line BIST
- Scan-Based Techniques and Boundary Scan
- Self-Repair Methodologies
- Signal Integrity Test
- System Test
- Test of Embedded Cores and System-on-Chip
- Test of MCMs and Boards
- Test Resource Partitioning and Embedded Test
- Test Synthesis and Synthesis for Testability
- Thermal Testing
- Yield Analysis and Yield Enhancement

Submissions: For the Research Track, the Program Committee invites original submissions focusing on novel concepts and methodologies; full paper submissions are preferred. For the Application Track, extended abstract or full paper submissions are invited focusing on case studies and reports on industrial and/or academic experiences, practices, and developments. All submissions should be at least one page A4; accepted final manuscripts should not exceed six pages A4.

Electronic submission in PDF via the workshop web page, which also informs about the review criteria for both tracks, is strongly encouraged. Please identify a contact author with complete information (mailing address, phone number, fax number, and e-mail address).

Proceedings: On site, ETW’03 will deliver handouts of the accepted contributions whose authors wish to provide the corresponding materials. After the workshop, formal proceedings of selected papers will be published by the IEEE Computer Society. The Program Committee will select the contributions to be included in the formal proceedings based on the review results and the quality of the papers included in the handouts. The best contributions will appear in a special issue of the Journal of Electronic Testing: Theory and Applications (JETTA), published by Kluwer Academic Publishers.

Key Dates:
- Extended submission deadline: February 9, 2003
- Notification of acceptance: March 15, 2003

IEEE TTTC Test Technology Educational Program (TTEP) 2003

TTEP 2003 tutorials will be offered during May 25 on emerging test technology topics. Tutorial proposals should be submitted according to the guidelines at http://tab.computer.org/tttc/teg/ttep by November 20, 2002.

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